A development of a Near-Field Optical Microcope

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(Dated: 29 de abril de 2022)

There exist a lot of Scanning Probe Microscopy Systems, such as Atomic Force Microscopy (AFM) that use a metallic tip and are used to get a image with nanometric resolution, but they are expensive and in some cases need special conditions for operation, in other hand, the Near-Field Scanning Optical Microscopy (NSOM) systems use a dielectric tip and the interaction between the tip and the sample is due optical processes. In this work we show the first results of the development of a Near-Field Microscope where its artisanal construction gives it some advantages from comercial ones.

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